

**Search Notes**

Application/Control No.

10/661,824

Examiner

Yixing Qin

Applicant(s)/Patent under  
Reexamination

CHIZAWA ET AL.

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed text searching for detection of abnormalities on substrates	12/26/2007	YQ